

GP120R60T4

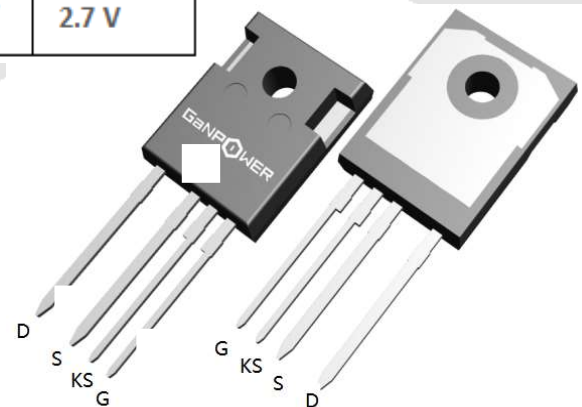
N-channel 1100V 30A GaNPower HEMT in TO247-4 Package

Datasheet version 1.0 Preliminary

Features

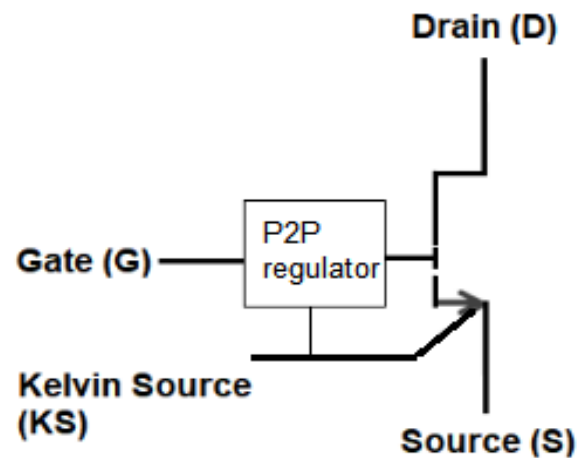
BV_{dss}	R_{dson}	I_{ds}	Q_g	V_{GS}	$V_{gs}(TH)$
1100 V	60 mΩ	30 A	8.25 nC	-20 to 20V	2.7 V

- Ultra-low RDS(on)
- High dv/dt capability
- Extremely low input capacitance
- Zero Qrr
- Outstanding switching performance
- Low Profile
- Upgraded P2P-GaN with input regulator IC to match input lead and voltage of existing SiC MOSFET**



Applications

- Switching Power Applications
- Server and Telecom Power Application
- EV OBC and DC-DC Converters
UPS, Inverters, PV



Description

These devices are N-channel 1100 V Power GaN HEMTs based on proprietary E-mode GaN on silicon technology, integrating an input regulator circuit to match input lead and voltage of existing SiC MOSFET in a pin to pin fashion. The resulting product has extremely low on state resistance, very low input capacitance and zero reverse recovery charge making it especially suitable for applications which require superior power density, ultra-high switching frequency and outstanding efficiency.

Device Characteristics

Static Parameters				Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	$V_{GS(TH)}$	Gate threshold voltage	$V_{ds}=V_{gs}, I_d=21\text{ mA}$ ($T_J=25^\circ\text{C}$)	1.5	2.7	4	V
2	V_{GS}^1	Gate-Source voltage range		-20		20	V
3	BV_{dss}^2	Drain-Source breakdown voltage	$V_{gs}=0V, I_d < 1\text{ mA}$ ($T_J=25^\circ\text{C}$)		1100		V
4	I_{dss}	Zero gate voltage drain leakage current	$V_{gs}=0V, V_{ds}=1100V$ $T_J=25^\circ\text{C}$		250	950	μA
5	I_{gss}	Gate-Source Leakage	$V_{gs} = 6V, V_{ds} = 0V$		0.7	30	mA
6	R_{dson}	drain-source on resistance	$V_{gs}=6.5V, I_d=6A$ $T_J=25^\circ\text{C}$		42	60	m Ω
7	V_{sd}	Reverse conduction voltage	$I_{sd}=0.5A, V_{gs}=0V$	1.2	2.0	3	V
8	R_g	Gate resistance	$f=25\text{MHz}$ Open drain		1.5		Ω
Dynamic Parameters				Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	C_{ISS}	Input capacitance	$V_{gs} = 0\text{ V}$		236		pf
2	C_{OSS}	Output capacitance	$V_{ds} = 700\text{ V}$		72		pf
3	C_{RSS}	Reverse transfer capacitance	$f = 1\text{MHz}$		4.6		pf
4	Q_g	Gate charge	$V_{ds} = 400V$		8.25		nC
5	Q_{gs}	Gate to source charge	$I_d = 9A$		1.5		nC
6	Q_{gd}	Gate to drain charge	$V_{gs} = 6V$		1.8		nC
7	Q_{rr}	Reverse recovery charge			0		nC
Switching Performance				Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	$t_{d(on)}$	Turn-on delay time	$V_{ds} = 800V$		34		ns
2	t_r	Rise time	$I_d = 15A$		26		ns

¹ A wider range of gate driving from -20V to 20V can be accepted, but recommended range is still -3V to 6V. Wider range protects the gate from damage, but at some cost of power loss.

² BV_{dss} refers to DC withstanding voltage. This product is recommended for DC bus voltage of 800-1000V.

3	$t_{d(off)}$	Turn-off delay time	$R_g = 10\Omega$ $V_{GS} = -3/6.5V$	33	ns
4	t_f	Fall time		20	ns

Absolute Max. Ratings

	Symbols	Parameters	Value	Unit
1	V_{DS-max}	Breakdown voltage transient @ $T_{case}=25^{\circ}C$	1100	V
2	V_{DS-max}	Breakdown voltage transient @ $T_{case}=125^{\circ}C$	1000	V
3	V_{GS-max}	Gate to source max. voltage @ $T_{case}=25^{\circ}C$	-12 to +7.5	V
4	I_{ds-max}	Drain to source pulse current @ $T_{case}=25^{\circ}C$, pulse width 10 μs , $V_{GS} = 6 V$	30	A
5	I_{ds-max}	Drain to source pulse current @ $T_{case}=150^{\circ}C$	22	A
6	$dv/dt-max$	Drain to source voltage slew rate	200	V/ns
7	T_J-max	Max junction temperature	150	$^{\circ}C$
8	$T_S-storage$	Storage temperature	-55 to 150	$^{\circ}C$

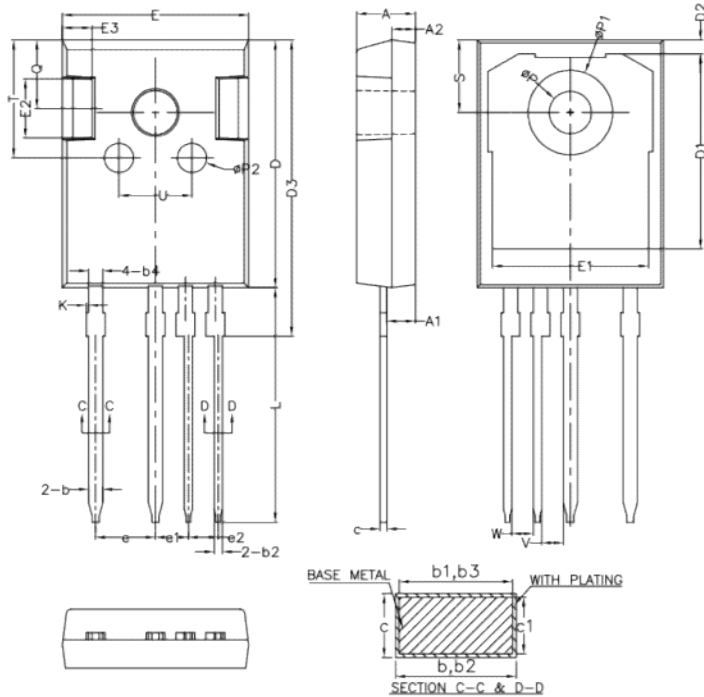
Thermal and Soldering Characteristics (Typical)

	Symbols	Parameters	Value	Unit
1	R_{thJC}	Thermal resistance (junction to case)	0.6	$^{\circ}C/W$
2	R_{thJA}	Thermal resistance (junction to ambient)	62	$^{\circ}C/W$
3	T_{solder}	Reflow soldering temperature	250	$^{\circ}C$

Ordering

Order Code	Package Type	Packaging Method	Qty
GP120R60T4	TO274-4 surface mount, bottom cooled	3	

Package Information



COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16	-	1.29
b1	1.15	1.20	1.25
b2	0.66	-	0.79
b3	0.65	0.70	0.75
b4	1.16	-	1.29
c	0.59	-	0.66
c1	0.58	0.60	0.62
D	20.90	21.00	21.10
D1	16.25	16.55	16.85
D2	1.05	1.20	1.35
D3	24.97	25.12	25.27
E	15.70	15.80	15.90
E1	13.10	13.30	13.50
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
e	4.98	5.08	5.18
e1	2.69	2.79	2.89
e2	2.44	2.54	2.64
K	0	-	0.20
L	19.80	19.92	20.10
P	3.50	3.60	3.70
P1	-	-	7.40
P2	2.40	2.50	2.60
Q	5.60	-	6.00
S	6.00	6.15	6.30
T	9.80	-	10.20
U	6.00	-	6.40
V	1.44	1.84	2.24
W	1.44	1.84	2.24

NOTES:
 1. ALL DIMENSIONS DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.
 2. EJECTION MARK DEPTH $0.10^{+0.15}_{-0.05}$.



GaNPower International Inc.

Further information

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Data Source– Data here are based on recent tests but all parameters may not be up to date. Actual final test data from packaging production are available for selected customers upon request.